

AMENDMENTS TO THE CLAIMS:

1. (original) In a disc drive comprising at least one disc having a plurality of addressable sectors arranged in a plurality of tracks on a surface of the disc, the sectors being categorised into zones such that data is capable of being written to and read from different zones at different rates, a method of storing information on defective sectors comprising steps of:
 - (a) sorting defective sectors by zone;
 - (b) defining a cluster comprising at least one defective sector;
 - (c) selecting one sector from the cluster to be a reference sector;
 - (d) defining parameters with reference to the reference sector, the parameters describing the shape and size of the cluster;
 - (e) storing the parameters with an address of the reference sector; and
 - (f) performing the steps (b) to (e) separately for each zone.
2. (previously presented) A method of Claim 1 wherein the defining step (b) further comprises a step of including at least one non-defective sector in the cluster.
3. (original) A method of Claim 1 wherein the selecting step (c) includes selecting the sector with the smallest address to be the reference sector.
4. (original) A method of Claim 1 wherein the selecting step (c) includes selecting the sector with the largest address to be the reference sector.
5. (original) A method of Claim 1 wherein the defining step (d) further includes defining a scratch parameter characterizing the number of tracks covered by the cluster.
6. (original) A method of Claim 1 wherein the defining step (d) further includes defining a span parameter characterizing the number of sectors covered by the cluster along each track.
7. (previously presented) A method of Claim 1 wherein the defining step (d) further includes defining an angle parameter characterizing the angular deviation of a side of the cluster from a reference line intersecting the reference sector.

8. (previously presented) A method of Claim 7 further comprising defining a radial line to be the reference line.
9. (previously presented) A method comprising steps of:
 - (a) defining a cluster comprising at least one defective location;
 - (b) selecting one location from the cluster to be a reference location;
 - (c) defining parameters with reference to the reference location; and
 - (d) storing the parameters with an address of the reference location.
10. (previously presented) The method of claim 9 wherein the parameters are stored in a storage apparatus.
11. (previously presented) The method of claim 9 wherein the locations are sectors.
12. (previously presented) The method of claim 9 further comprising the steps of:
sorting a plurality of defective locations into zones; and
performing steps a-d for each zone.
13. (cancelled)
14. (new) A method comprising the steps of:
 - (a) defining a defect cluster that includes a reference location; and
 - (b) determining defect parameters relative to the reference location.
15. (new) The method of claim 14 further comprising the step of storing the parameters with an address of the reference location.
16. (new) The method of claim 15 wherein the parameters and address of the reference location are used to determine defect information.

17. (new) The method of claim 15 wherein the defect information corresponds to defects of a storage device.